

JOURNAL OF ELECTRONIC TESTING:  
Theory and Applications  
(JETTA)

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ELECTRONIC  
TESTING  
Theory and Applications (JETTA)

Editor in Chief: Vishwani Agrawal

Volume 39, Numbers 5–6, December 2023

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Volume 39, Numbers 5–6, December 2023 535–678

A journal serving electronic test professionals  
in concurrence with the Test Technology Technical Council  
(TTTC) of the IEEE Computer Society



Springer



ISSN: 0923-8174